





# Phase Control Thyristor Preliminary Information

DS5949-1.0 September 2009 (LN26869)

## **FEATURES**

- Double Side Cooling
- High Surge Capability

#### **APPLICATIONS**

- High Power Drives
- · High Voltage Power Supplies
- Static Switches

# **VOLTAGE RATINGS**

Part and Ordering Number	Repetitive Peak Voltages VDRM and VRRM V	Conditions
DCR1650C65* DCR1650C60 DCR1650C55 DCR1650C50	6500 6000 5500 5000	$\begin{split} T_{vj} &= \text{-}40^\circ\text{C} \text{ to } 125^\circ\text{C},\\ I_{DRM} &= I_{IRRM} = 300\text{mA},\\ V_{DRM}, V_{RRM}t_p &= 10\text{ms},\\ V_{DSM} \& V_{RSM} &= \\ V_{DRM} \& V_{RRM} + 100V\\ \text{respectively} \end{split}$

Lower voltage grades available. \* 6200V @ -40° C, 6500V @ 0° C

## ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

## DCR1650C65

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

## **KEY PARAMETERS**

V <sub>DRM</sub>	6500V
I <sub>T(AV)</sub>	1650A
ITSM	22000A
dV/dt*	1500V/μs
dl/dt	300A/μs

\* Higher dV/dt selections available

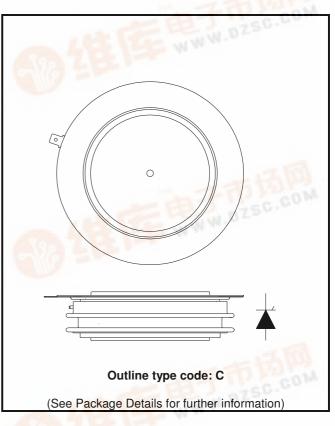


Fig. 1 Package outline





## **CURRENT RATINGS**

## $T_{\text{case}}$ = 60 °C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Double Sid	de Cooled			
I <sub>T(AV)</sub>	Mean on-state current	Half wave resistive load	1650	Α
I <sub>T(RMS)</sub>	RMS value	-	2590	Α
I <sub>T</sub>	Continuous (direct) on-state current	-	2575	А

## **SURGE RATINGS**

Symbol Parameter		Test Conditions	Max.	Units
I <sub>TSM</sub>	Surge (non-repetitive) on-state current	10ms half sine, T <sub>case</sub> = 125 ℃	22.0	kA
l <sup>2</sup> t	I <sup>2</sup> t for fusing	$V_R = 0$	2.42	MA <sup>2</sup> s

# THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
R <sub>th(j-c)</sub>	Thermal resistance – junction to case	Double side cooled DC		-	0.0101	°C/W
		Single side cooled	Anode DC	-	0.0176	°C/W
			Cathode DC	-	0.0239	°C/W
R <sub>th(c-h)</sub>	Thermal resistance – case to heatsink	Clamping force 37kN	Double side	-	0.0025	°C/W
		(with mounting compound)	Single side	-	0.005	°C/W
$T_{vj}$	Virtual junction temperature	Blocking V <sub>DRM</sub> / <sub>VRRM</sub>		-	125	℃
T <sub>stg</sub>	Storage temperature range			-55	125	℃
F <sub>m</sub>	Clamping force			33	41	kN

#### semiconductor 查询"DCR1650C65"供应商

# **DYNAMIC CHARACTERISTICS**

Symbol	Parameter	Test Conditions		Min.	Max.	Units
I <sub>RRM</sub> /I <sub>DRM</sub>	Peak reverse and off-state current	At V <sub>RRM</sub> /V <sub>DRM</sub> , T <sub>case</sub> = 125℃		-	300	mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V <sub>DRM</sub> , T <sub>j</sub> = 125℃, ga	ite open	-	1500	V/µs
dl/dt	Rate of rise of on-state current	From 67% V <sub>DRM</sub> to 2x I <sub>T(AV)</sub>	Repetitive 50Hz	-	150	A/μs
		Gate source 30V, 10Ω,	Non-repetitive	-	300	A/μs
		t <sub>r</sub> < 0.5μs, T <sub>j</sub> = 125℃				
$V_{T(TO)}$	Threshold voltage – Low level	100A to 1500A at T <sub>case</sub> = 125	5℃	-	1.0	V
	Threshold voltage – High level	1500A to 7200A at T <sub>case</sub> = 125℃		-	1.2	V
r <sub>T</sub>	On-state slope resistance – Low level	100A to 1500A at T <sub>case</sub> = 125 ℃		-	0.615	mΩ
	On-state slope resistance – High level	1500A to 7200A at T <sub>case</sub> = 125℃		-	0.5	mΩ
t <sub>gd</sub>	Delay time	$V_D = 67\% \ V_{DRM}$ , gate source 30V, $10\Omega$		-	3	μs
	·	t <sub>r</sub> = 0.5μs, T <sub>j</sub> = 25 ℃				
t <sub>q</sub>	Turn-off time	$T_j = 125 ^{\circ}\text{C}, \ V_R = 200 ^{\circ}\text{V}, \ dI/dt = 1 ^{\circ}\text{A}/\mu \text{S},$		-	1200	μs
		dV <sub>DR</sub> /dt = 20V/μs linear				
Qs	Stored charge	$I_T = 2000A$ , $T_j = 125$ °C, $dI/dt - 1A/\mu s$ ,		2000	4500	μC
ΙL	Latching current	$T_j = 25$ °C, $V_D = 5$ V		-	3	Α
lн	Holding current	$T_j = 25 ^{\circ}\text{C},  R_{G-K} = \infty,  I_{TM} = 500$	0A, I <sub>T</sub> = 5A	-	300	mA



## **GATE TRIGGER CHARACTERISTICS AND RATINGS**

Symbol	Parameter	Test Conditions	Max.	Units
$V_{GT}$	Gate trigger voltage	V <sub>DRM</sub> = 5V, T <sub>case</sub> = 25 ℃	1.5	V
$V_{GD}$	Gate non-trigger voltage	At 50% V <sub>DRM</sub> , T <sub>case</sub> = 125 ℃	0.4	V
I <sub>GT</sub>	Gate trigger current	V <sub>DRM</sub> = 5V, T <sub>case</sub> = 25 ℃	250	mA
I <sub>GD</sub>	Gate non-trigger current	At 50% V <sub>DRM</sub> , T <sub>case</sub> = 125 ℃	15	mA

## **CURVES**

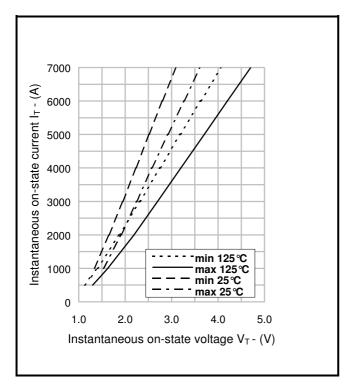


Fig.2 Maximum & minimum on-state characteristics

 $V_{TM}$  **EQUATION** Where A = 0.666848 B = 0.033446

 $V_{TM} = A + Bln (I_T) + C.I_T + D.\sqrt{I_T}$  C = 0.000418

D = 0.009666

these values are valid for  $T_j = 125$  °C for  $I_T$  100A to 7200A





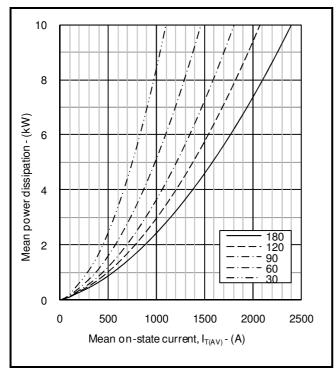


Fig.3 On-state power dissipation - sine wave

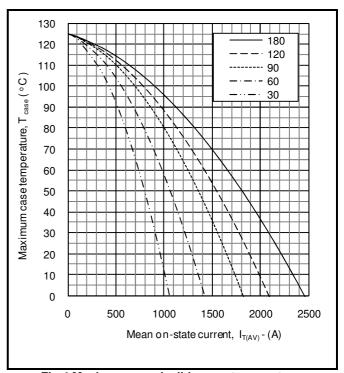


Fig.4 Maximum permissible case temperature, double side cooled – sine wave

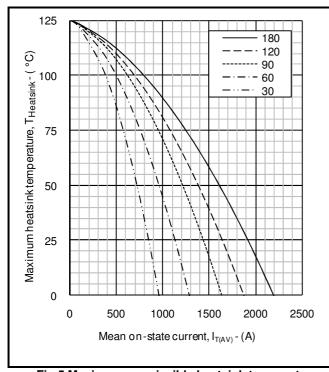


Fig.5 Maximum permissible heatsink temperature, double side cooled – sine wave

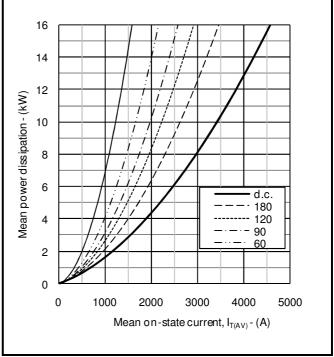


Fig.6 On-state power dissipation - rectangular wave

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# 查询"DCR1650C65"供应商

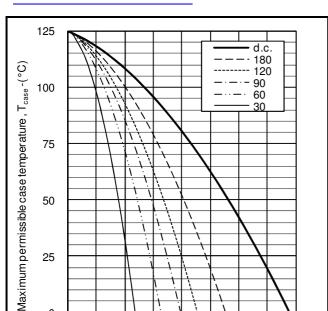


Fig.7 Maximum permissible case temperature, double side cooled - rectangular wave

500 1000 1500 2000 2500 3000 3500 4000 Mean on-state current,  $I_{T(AV)}$  - (A)

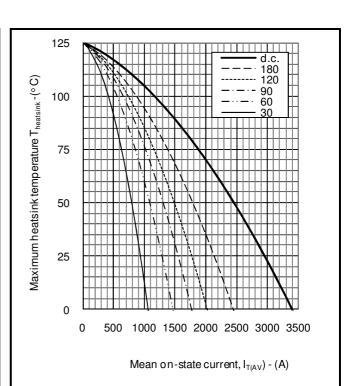
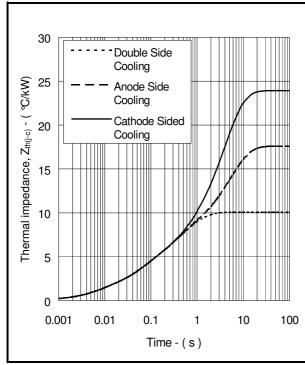


Fig.8 Maximum permissible heatsink temperature, double side cooled - rectangular wave



		1	2	3	4
Double side cooled	R <sub>i</sub> (°C/kW)	1.1043	2.576	4.5096	1.9009
	T <sub>i</sub> (s)	0.006176	0.0517916	0.3820376	1.06
Anode side cooled	R <sub>i</sub> (°C/kW)	1.0977	2.4566	4.0469	9.9994
	T <sub>i</sub> (s)	0.006153	0.050142	0.3129407	5.27
Cathode side cooled	R <sub>i</sub> (℃/kW)	1.1519	2.8926	2.4064	17.4793
	T <sub>i</sub> (s)	0.006389	0.0582953	0.3775516	3.97

$$Z_{th} = \sum [R_i \times (1-exp. (t/t_i))]$$

 $\Delta R_{\text{th(j-c)}}$  Conduction

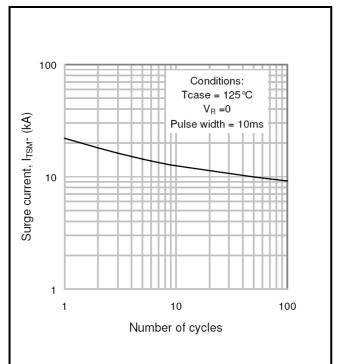
Tables show the increments of thermal resistance  $R_{\text{th}(j\cdot c)}$  when the device operates at conduction angles other than d.c.

	Double side cooling			Anode Side Cooling			
	$\Delta Z_{th}$ (	$\Delta Z_{th}$ (z)		$\Delta Z_{th}$		(z)	
θ°	sine.	rect.		θ°	sine.	rect.	
180	1.95	1.26		180	1.95	1.26	
120	2.32	1.89		120	2.32	1.89	
90	2.74	2.27		90	2.74	2.27	
60	3.14	2.70		60	3.14	2.70	
30	3.46	3.19		30	3.46	3.19	
15	3.61	3.47		15	3.62	3.47	

Anode Side Cooling				
	$\Delta Z_{th}(z)$			
θ°	sine.	rect.		
180	1.95	1.26		
120	2.32	1.89		
90	2.74	2.27		
60	3.14	2.70		
30	3.46	3.19		

Cathode Sided Cooling				
	$\Delta Z_{t}$	<sub>h</sub> (z)		
θ°	sine.	rect.		
180	1.95	1.26		
120	2.31	1.88		
90	2.72	2.26		
60	3.12	2.68		
30	3.43	3.17		
15	3.58	3.44		

Fig.9 Maximum (limit) transient thermal impedance – junction to case (°C/kW)



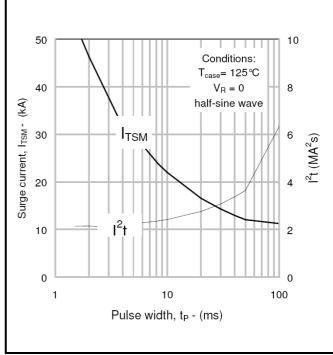


Fig.10 Multi-cycle surge current

Fig.11 Single-cycle surge current

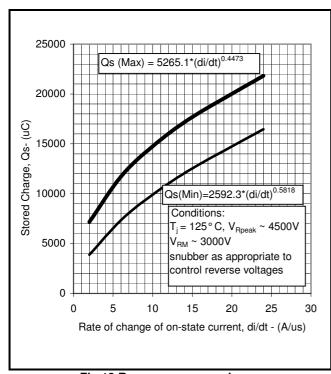


Fig.12 Reverse recovery charge

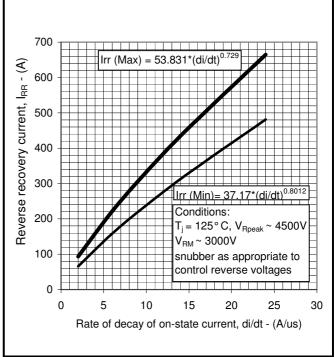


Fig.13 Reverse recovery current

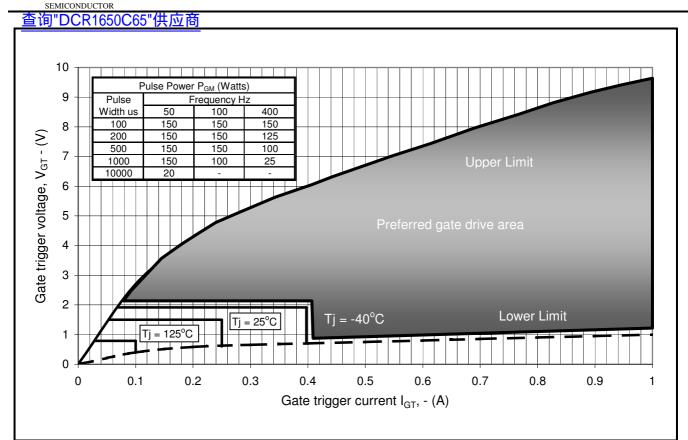


Fig14 Gate Characteristics

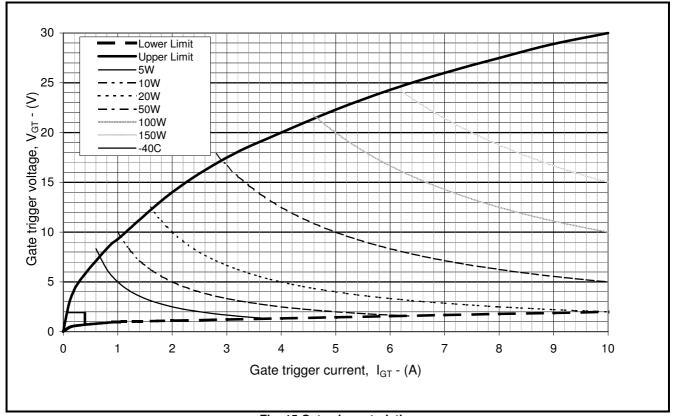


Fig. 15 Gate characteristics

PACKAGE DETAILS



For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

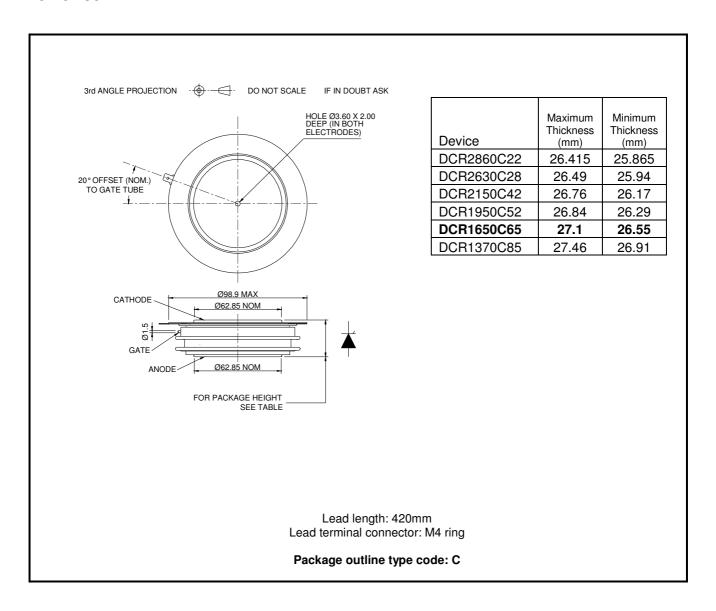


Fig.16 Package outline



#### **POWER ASSEMBLY CAPABILITY**

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

#### **HEATSINKS**

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



http://www.dynexsemi.com

e-mail: power solutions@dynexsemi.com

HEADQUARTERS OPERATIONS DYNEX SEMICONDUCTOR LTD

Doddington Road, Lincoln Lincolnshire, LN6 3LF. United Kingdom.

Tel: +44(0)1522 500500 Fax: +44(0)1522 500550 **CUSTOMER SERVICE** 

Tel: +44(0)1522 502753 / 502901. Fax: +44(0)1522 500020

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